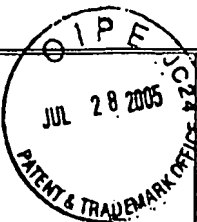


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M122-1897SERIAL NO.
10/050,347APPLICANT
Gurtej S. SandhuFILING DATE
January 15, 2002GROUP
2813

U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>RL</i>	AA	3,627,598	12/71	McDonald et al.			
	AB	4,254,161	03/81	Kemlage			
	AC	4,262,631	04/81	Kubacki			
	AD	4,435,447	03/84	Ito et al.			
	AE	4,882,649	11/89	Chen et al.			
	AF	4,891,684	01/90	Nishioka et al.			
	AG	4,980,307	12/90	Ito et al.			
	AH	4,996,081	02/91	Ellul et al.			
	AI	5,051,794	09/91	Mori			
<i>RL</i>	AJ	5,142,438	08/92	Reinberg et al.			

FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
<i>RL</i>	AK	EP 0886308 A2	12/98	EPO				
<i>RL</i>	AL	237243 a	04/01	Japan				
	AM							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

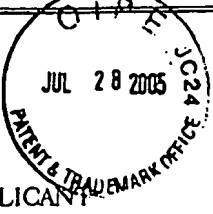
<i>RL</i>	AN	Wolf, Stanley, <i>Silicon Processing for the VLSI Era</i> (1995), V.3, 648-9
<i>RL</i>	AO	Laughery et al., <i>Effect of H₂ Content on Reliability of Ultrathin In-Situ Steam Generated (ISSG) SiO₂</i> , Sept., 2000, Vol. 21, No. 9.
	AP	

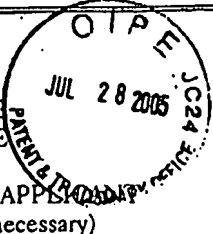
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Form PTO-1449				ATTY. DOCKET NO. MI22-1898		SERIAL NO. 10/050, 347		
U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE				APPLICANT Gurtej S. Sandhu				
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U.S. PATENT DOCUMENTS								
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate	
<i>JS</i>	AA	5,227,651	07/93	Kim et al.				
	AB	5,237,188	08/93	Iwai et al.				
	AC	5,324,679	06/94	Kim et al.				
	AD	5,330,936	07/94	Ishitani				
	AE	5,350,707	09/94	Ko et al.				
	AF	5,376,593	12/94	Sandhu et al.				
	AG	5,393,702	02/95	Yang et al.				
	AH	5,397,748	03/95	Watanabe et al.				
	AI	5,398,641	03/95	Shih				
<i>JS</i>	AJ	5,459,105	10/95	Matsuura				
FOREIGN PATENT DOCUMENTS								
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	AL							
	AM							
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
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EXAMINER		DATE CONSIDERED <i>Naresh Schuler</i> 12/2/05						
<p>*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>								

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U.S. PATENT DOCUMENTS							
Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>[Signature]</i>	AA	5,498,890	03/96	Kim et al.	—	—	
	AB	5,504,029	04/96	Murata et al.	—	—	
	AC	5,508,542	04/96	Geiss et al.	—	—	
	AD	5,523,596	06/96	Ohi et al.	—	—	
	AE	5,731,235	03/98	Srinivasan et al.	—	—	
	AF	5,821,142	10/98	Sung et al.	—	—	
	AG	5,844,771	12/98	Graettinger et al.	—	—	
	AH	5,851,603	12/98	Tsai et al.	—	—	
	AI	5,882,978	03/99	Srinivasan et al.	—	—	
<i>[Signature]</i>	AJ	6,001,741	12/99	Alers	—	—	

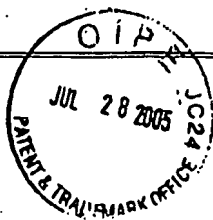
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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>JS</i>	AA	6,001,748	12/99	Tanaka			
	AB	6,008,104	12/99	Schrems			
	AC	6,051,865	04/00	Gardner et al.			
	AD	6,063,713	06/00	Doan			
	AE	6,077,754	06/00	Srinivasan et al.			
	AF	6,096,597	08/00	Tsu et al.			
	AG	6,111,744	08/00	Doan			
	AH	6,168,980	01/01	Yamazaki et al.			
	AI	6,207,985 B1	03/01	Walker			
<i>JS</i>	AJ	6,323,138 B1	11/01	Doan			

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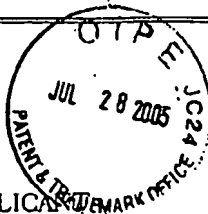
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U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
<i>JS</i>	AA	6,348,420 B1	02/02	Raaijmakers et al.			
	AB	6,265,327	07/01	Kobayashi et al.			
	AC	6,350,707 B1	02/02	Liu et al.			
	AD	6,723,599 B2	04/04	Eppich et al.			
	AE	6,893,981 B2	05/05	Park et al.			
	AF	09/653,281	08/00	Beaman et al.			
	AG	2001/0036752	11/01	DeBoer et al.			
	AH	2002/0009861	08/98	Narvankar et al.			
	AI	2002/0052124	05/02	Raaijmakers et al.			
<i>JS</i>	AJ	2003/0034518A1	02/03	Yoshikawa			

FOREIGN PATENT DOCUMENTS

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